

SCOPE

To perform Inductance and Capacitance testing on Electrical socket contacts as manufactured and submitted by the test sponsor.

APPLICABLE DOCUMENTS

Standards:

MIL-STD-1344 EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1. The following test samples were submitted by the test sponsor for the evaluation to be performed by Contech Research, Inc.
 - 5, Mounted contacts, P/N SMSP1001 10, Loose contacts
- 2. The following additional materials were submitted by the test sponsor to assist and perform the testing of items listed in #1 above.
 - 1, Contact holding block
 - 4, Test boards
- 3. Test boards for mounting test samples were supplied by the test sponsor.
- 4. The test samples were not cleaned prior to testing.
- 5. Unless otherwise specified in the test procedures used, no further preparation was used.

PROJECT NO.: 99360 SPECIFICATIONS: EIA-364

PART NO.: SMSP1001 PART DESCRIPTION: Socket Contacts

SAMPLE SIZE: 5 Contacts TECHNICIAN: MO

START DATE: 6/4/99 COMPLETE DATE: 6/4/99

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ROOM AMBIENT: 22°C RELATIVE HUMIDITY: 40%

EQUIPMENT ID#: 473, 474, 1053, 1057

<u>CAPACITANCE</u>

PURPOSE:

To determine the capacitance characteristics between contacts within the assembled test unit.

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PROCEDURE:

1. The test was performed in accordance with EIA 364, TP 30.

2. Test Conditions:

Frequency : 500 MHzPolarization : None

• Mounting Conditions : In housing, Mounted to PCB

Adjacent Contacts : YesMating Conditions : Unmated

No. of Observations : 5

- 3. A network analyzer was used to perform the measurements.
- Said analyzer was interconnected to a controlled impedance probe station and S-parameter test set.
- 5. The entire system (without the sample installed) was calibrated using the precision substrate matching the probes used.
- 6. Following calibration, the test sample was probed at the contact interface and the capacitance was measured and recorded.